

ABSTRACT OF THE DISCLOSURE

A device testing system comprising automated test equipment (ATE) configured to interface to a device under test (DUT) and logic configured to select a test set of data comprising a plurality of test pairs, the test pairs indicative of DUT parameter values, the logic further configured to select a subset of the plurality of test pairs from the test set of data and to test the DUT via the ATE with a portion of the selected subset based upon the test results of at least one of the test pairs.